



Integrated Device Technology, Inc.
6024 Silver Creek Valley Road, San Jose, CA - 95138

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: TB1801-01 DATE: 9-Feb-2018 Product Affected: 4RCD0229KB1ATG, 4RCD0229KB1ATG8, 4RCD0229KB1ATG/M, 4RCD0229KB1ATG8/M Date Effective: 9-May-2018	MEANS OF DISTINGUISHING CHANGED DEVICES: <input type="checkbox"/> Product Mark <input type="checkbox"/> Back Mark Traceability to the test location is <input type="checkbox"/> Date Code maintained by IDT and available on <input checked="" type="checkbox"/> Other request
---	--

Contact: IDT PCN DESK E-mail: pcndesk@idt.com	Attachment: <input checked="" type="checkbox"/> Yes <input type="checkbox"/> No Samples: Please contact your local sales representative for sample request.
---	---

DESCRIPTION AND PURPOSE OF CHANGE:

<input type="checkbox"/> Die Technology <input type="checkbox"/> Wafer Fabrication Process <input type="checkbox"/> Assembly Process <input type="checkbox"/> Equipment <input type="checkbox"/> Material <input type="checkbox"/> Testing <input checked="" type="checkbox"/> Manufacturing Site <input type="checkbox"/> Data Sheet <input type="checkbox"/> Other	<p>This notification is to advise our customers that IDT is adding ASEK, Taiwan as an alternate facility for Test process for the selective products that are presently tested at IDT Penang, Malaysia facility.</p> <p>Attachment I details the change.</p>
--	--

RELIABILITY/QUALIFICATION SUMMARY:

There is no expected change to the product quality or reliability performance. Please refer to Attachment I for Electrical correlation data.

CUSTOMER ACKNOWLEDGMENT OF RECEIPT:

IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.

IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.

Customer: _____	<input type="checkbox"/> <i>Approval for shipments prior to effective date.</i>
Name/Date: _____	E-Mail Address: _____
Title: _____	Phone# /Fax# : _____

CUSTOMER COMMENTS: _____

IDT ACKNOWLEDGMENT OF RECEIPT:

RECD. BY: _____ DATE: _____



Integrated Device Technology, Inc.
6024 Silver Creek Valley Road, San Jose, CA - 95138

PRODUCT/PROCESS CHANGE NOTICE (PCN)

ATTACHMENT I - PCN # : TB1801-01

PCN Type: Manufacturing Site - Alternate Test Location

Data Sheet Change: None

Detail Of Change:

This notification is to advise our customers that IDT is adding ASEK, Taiwan as an alternate facility for Test process for the selective products that are presently tested at IDT Penang, Malaysia facility.

This change will allow IDT the flexibility to ship from either facility and will provide the increased capacity, flexibility and shorter lead time to meet market demand.

There is no change in the Test processing flows. Load boards and test programs are the same at both qualified facilities. IDT has completed the electrical test correlation and based on the test results we do not anticipate any impact on device performance. The testing is fully compatible and transferrable between the test facilities with no change to the test coverage.

There is no change in the moisture sensitivity level (MSL).

If you require samples to conduct evaluations, please contact your local sales representative to acknowledge this PCN and request samples.



Integrated Device Technology, Inc.
6024 Silver Creek Valley Road, San Jose, CA - 95138

PRODUCT/PROCESS CHANGE NOTICE (PCN)

ATTACHMENT I - PCN # : TB1801-01

Qualification Information and Qualification Data:

Electrical Test Correlation Results

Vehicle: 4RCD0229KB1ATG
Sample size: 2370 electrically good units tested by handler
10 good and 10 reject units tested by handler

Description	Existing Test (IDT - IDT, Penang)	Alternate Test (ASEK, Taiwan)
Tester Platform	PS9G	PS9G
Loadboard	(DDR4_C0)-ATG253-Y-37- 02A_305-PD-13-0928	(DDR4_C0)-ATG253-Y-37- 02A_305-PD-13-0928
Test Program	CK_4RCD0229SCB1_ZNI_EPS ON_REV10_SCD1078_ALLBI N	CK_4RCD0229SCB1_ZNI_EPSON _REV10_SCD1078_ALLBIN
Test Site	Quad Site	Quad Site
Test Temperature	105°C	105°C
Test Correlation Results	100%	100%
Number of Good Units Correlated	2370 pcs	2370 pcs
1627 units Bin 1 run	Passed	Passed
10 good units datalog correlation	Passed	Passed
10 reject units datalog correlation	Passed	Passed